

Notice of References Cited

Application/Control No.

10/044,401

Examiner

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Art Unit
Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,411,230 B1	06-2002	Tauchen et al.	341/101
	В	US-6,570,876 B1	05-2003	Aimoto, Takeshi	370/389
	С	US-6,363,452 B1	03-2002	Lach, Jorge E.	710/316
. `	D	US-6,249,528 B1	06-2001	Kothary, Piyush	370/466
	E	.US-2002/0186656 A1	12-2002	Vu, Chuong D.	370/229
	F	US-6,324,613 B1	11-2001	Aguilar et al.	710/316
	G	US-5,941,941 A	08-1999	Hasegawa, Satoshi	708/551
	Н	·US-5,313,586 A	05-1994	Rutman, Serge	712/34
	1	US-			
	. J	US-			
	К	US-			
	· L	US-			
	,M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11265341 A	09-1999	Japan	HIRATA, AKIRA	G06F 13/36
	0					
	Р					
	α					
	R					
	s					,
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	J	
	٧	
	V	
•	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.